

		02.11.2011
RefMat No 62		Category 1 Depth profiling resolutio
COMAR		Category 2
-5/26/17 × 4/2-2	Included in OMAR Database:	Category 3
	Green 1> YES Blue 0> NO	Category 4
		Category 5
Name of RM: Standard sample for in-depth profiling  Description Standard sample for in-depth profiling;		
Mo/Si multilayer		
Link http://www.ntt-at.com/products_e/sample_depth/index.html		
Certified (		
Film Thickness		20 nm Uncertainty %
Film Thickness		20 nm Uncertainty
	MeanValue Management	nm Uncertainty
	MeanValue  MeanValue	nm Uncertainty
,	iviean value	nm Uncertainty
Calibration of AES		Characterised by
Calibration of ESCA		Characterised by
Calibration of SIMS		Characterised by
Calibration of ToF-SIMS		Characterised by
Calibration of		Characterised by
2 Provider No Provider No 7		
		/company/data.html
Provider NTT Advanced Technology		
	Country	Japan
Contact Person	City	Tokyo, Nishi-shinjuku, Shinjuku-ku
Email	City Code	163-0431
Phone +81-3-5325-0711	Street + No	Shinjuku Mitsui Bldg., 2-1-1
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